

July 15, 2003

NEWS AND ANNOUNCEMENTS

Teradyne Introduces SafeTest™ Protection Technologies

SafeTest protection technologies protect today's newest low voltage devices against exposure to the over-voltage and over-current conditions common to conventional in-circuit test systems, providing electronics manufacturers with the safest, most accurate and risk-free solution for in-circuit testing. For more information on this technology, click here:

http://www.teradyne.com/prods/cbt/news/newsdesk/77news_pr_030610.html

UPCOMING EVENTS

Automated X-ray Inspection Strategies for High-Volume, Resource-Constrained Production Environments – a Complimentary Web Seminar – Tuesday, July 22, 2003

In this web seminar, you will learn about the capabilities of Automated Inspection Systems, and how to implement a solution to reduce the cost of ownership of an Automated X-ray Inspection test strategy by 66% while matching the beat rate of your production line. Additional program details and registration information are available at:

http://www.teradyne.com/prods/cbt/news/webinar/webinar_x-ray_07-22-2003.html

PRODUCT INFORMATION

Optima 7210™ Optical Process Test (OPT) System – In-process Test and Measurement of SMD Component Placement Performance – Data Sheet

The Optima 7210 optical process test system from Teradyne represents groundbreaking developments in PCBA vision technology, and an exciting alternative to earlier-generation machine vision systems. To access more information about this system's features and specifications, go to our web site at:

http://www.teradyne.com/prods/cbt/products/library/opt/Optima_7210.pdf

SafeTest™ Protection Technology for Accurate, Reliable, and Safe Testing of Today's New Low Voltage Technologies - Data Sheet

To read about the features of Teradyne's TestStation™ with SafeTest Protection Technologies, review the information on the product data sheet, which is available on our web site at:

<http://www.teradyne.com/prods/cbt/products/library/teststation/SafeTest.pdf>

TestStation LH™ In-Circuit Test System – Quality In-Circuit Test at an Affordable Price – Data Sheet

The TestStation LH in-circuit test system is a lower-cost, small footprint, feature scalable, version of Teradyne's popular, award winning TestStation 12X product family, which includes SafeTest protection technology. The features of the TestStation LH are highlighted on the product data sheet available on our web site at:

http://www.teradyne.com/prods/cbt/products/library/teststation/br_ts-lh.pdf

Download Teradyne's Design-to-Build™ (D2B) GenCAM Viewer for a Free 90-day Trial

This software download provides reading and viewing capabilities of GenCAM, GenCAD or D2B Alchemist™ project files. Click here for more information on how to download the GenCAM Viewer:
<http://www.teradyne.com/prods/cbt/products/soft-d2b/viewer.html>

RECENT TECHNICAL PAPERS, ARTICLES, & PUBLICATIONS

"AOI Moves Into High-Mix/Low-Volume Production" by John Arena (*EE-Evaluation Engineering*, May 2003)

Optical inspection currently is popular in high-volume applications, and future machine vision developments promise extraordinary improvements upon current possibilities. Automated Optical Inspection (AOI) has demonstrated that machine vision can work. Now the challenge for suppliers of equipment is to expand the technological solutions to deliver the true promises of machine vision: ease of use, comprehensive performance, and reliable diagnosis. For more information on this topic, click here:

http://www.teradyne.com/prods/cbt/products/library/aoi/AOI_High_Mix_Low_Vol.pdf

"Between Pressures and Remedies" by Amit Verma (*EPP Europe, Test Strategies in the Modern SMT Production Line – Part I – November/December 2002*)

The ever increasing pressures to reduce cost, increase quality and shorten time to market is an unending task in electronics manufacturing. To find out what is driving those pressures and what can remedy them, click here:

http://www.teradyne.com/prods/cbt/products/library/spectr/Verma_Opt_Test_Strat_EPP1.pdf

"Issues of Fault Coverage and Quality" by Amit Verma (*EPP Europe, Test Strategies in the Modern SMT Production Line – Part II – January/February 2003*)

Test strategies can provide advantages by improving the efficiency and quality of processes, and by driving cost reductions and improved performance through the entire product lifecycle. This article addresses the need for a profound test strategy and the issues of fault coverage and quality/reliability. Click here to read more on this topic:

http://www.teradyne.com/prods/cbt/products/library/spectr/Verma_Opt_Test_Strat_EPP2.pdf

"Teamster for Global Manufacturing" by Amit Verma (*EPP Europe, Test Strategies in the Modern SMT Production Line – Part III – March/April 2003*)

Reduced costs, increased quality, and shortened time to market – how can you attain these goals without compromising the product? To find out, read this article at:

http://www.teradyne.com/prods/cbt/products/library/spectr/Verma_Opt_Test_Strat_EPP3.pdf

"Management of DPMO Metrics Reduces the Cost of PCB Assembly" by Amit Verma (*Global SMT & Packaging*, April 2003)

Manufacturers can use DPMO metrics to reduce the cost of PCB assembly with fewer resources. Tools are now available to the industry that make use of DPMO data for strategic decision making applications. To read about these tools and review case study examples, click here for the English version:

<http://www.teradyne.com/prods/cbt/products/library/aoi/Verma%20Global%20SMT%20April%2003.pdf>

This article is also available in German (published in two parts by *Productronic* – May and June 2003).

Access Part I by clicking here:

http://www.teradyne.com/prods/cbt/products/library/general/Verma_DPMO_productronic.pdf

Access Part II by clicking here:

http://www.teradyne.com/prods/cbt/products/library/general/Verma_DPMO_productronic2.pdf

“Popularity in High-Volume Manufacturing” by John Arena and Pamela Lipson (EPP Europe, May/June 2003)

Automated Optical Inspection (AOI) has matured through several evolutionary phases, and with each increment has improved the value delivered to manufacturers as an element of an overall test and inspection strategy. From its origins as a replacement for inconsistent human-based inspection, the evolved AOI systems minimize defects, boost yields, and cut repair costs in high-volume SMT lines. To learn more about the continued evolution of AOI system with emerging technology alternatives, click here:

http://www.teradyne.com/prods/cbt/products/library/aoi/Arena%20EPP%205_6%202003.pdf

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<http://www.teradyne.com/prods/cbt/cbthome.html>

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